

Search Notes 				Application/Control No. 10/538,632 Examiner Hieu P. Nguyen	Applicant(s)/Patent under Reexamination OSMAN ET AL. Art Unit 2817	
SEARCHED				SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
Class	Subclass	Date	Examiner		DATE	EXMR
330	107	11/1/2007	HN	MOTTOLA STEVEN J	10/28/2007	HN
330	310	11/1/2007	HN			
330	98	11/1/2007	HN			
330	133	11/1/2007	HN			
330	150	11/1/2007	HN			
INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			